

# Slater & Matsil, L.L.P.

Suite 1000

17950 Preston Road

Dallas, Texas 75252

Phone: (972) 732-1001 Facsimile: (972) 732-9218

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To: Commissioner for Patents                          Fax: (703) 872-9318  
Art Unit 2812    Phone: (703) 306-3329

From: Ira Matsil    Pages: 2

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Applicant: Chen, *et al.*                                  Docket No: 2001 P 11914 US

Serial No.: 09/965,093                                  Art Unit: 2812

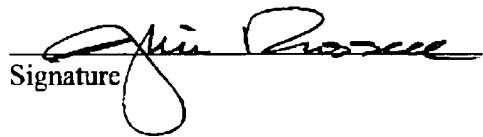
Filed: September 28, 2001                                  Examiner: Raevis, Robert R.

For: Direct, Non-Destructive Measurement of Recess Depth in a Wafer

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